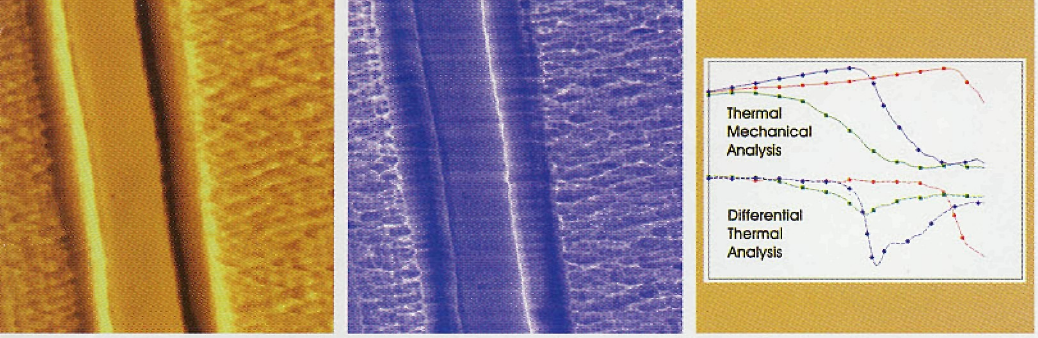
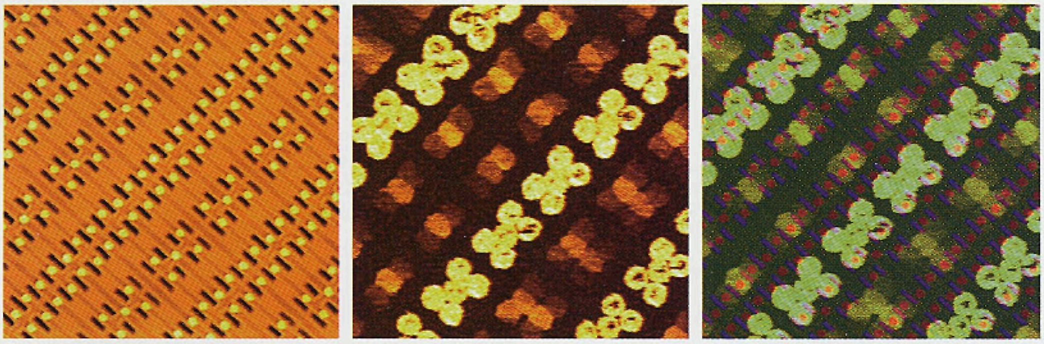
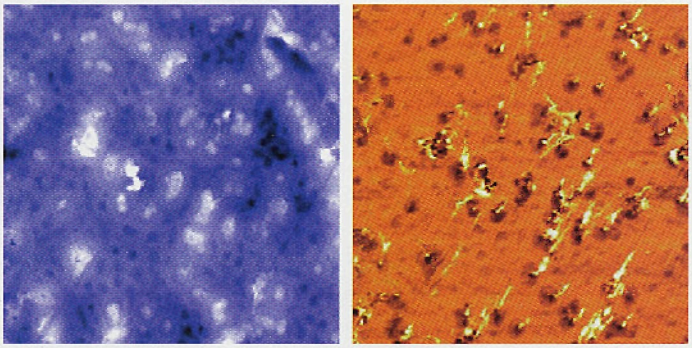


***Using topography, thermal conductivity mapping and micro thermal analysis identifies layers in a polymer film. Courtesy of Duncan Price, Loughborough.***



***Topography and electrostatic force images combine to show misalignment of contacts and implants in SRAM.***



| REGION GROUP | AREA µm² | % |
|---|---|---|
| Total area | 67.69 | 100 |
| Silicone lubricant | 3.101 | 4.6 |
| Teflon particles | 7.007 | 10.4 |

***Topography and phase images show area and percent coverage of Teflon® and lubricant in support matrix. Courtesy of Steve Pratt, Kodak.***

# When is an SPM more than a microscope?

## *(When it has PPT.™)*

PPT is Proximal Probe Technology.™ And it's only available in Scanning Probe Microscopes from ThermoMicroscopes.

Proximal Probe Technology gives you a whole lot more than just an image. It gives you the full range of proximity measurements you need to get accurate, precise and meaningful data in the engineering terms you recognize. Whether you want to measure friction, stiffness, adhesion, thermal conductivity, electrical or magnetic forces, or a host of other material properties, there's a ThermoMicroscopes system with PPT that's just right for the job. And for process characterization at the nanoscale level, nothing compares to the power PPT gives you.

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To learn more about PPT and proximity measurement tools, and to get a free copy of "*The Practical Guide to Scanning Probe Microscopy*," call, fax or visit our web site today.

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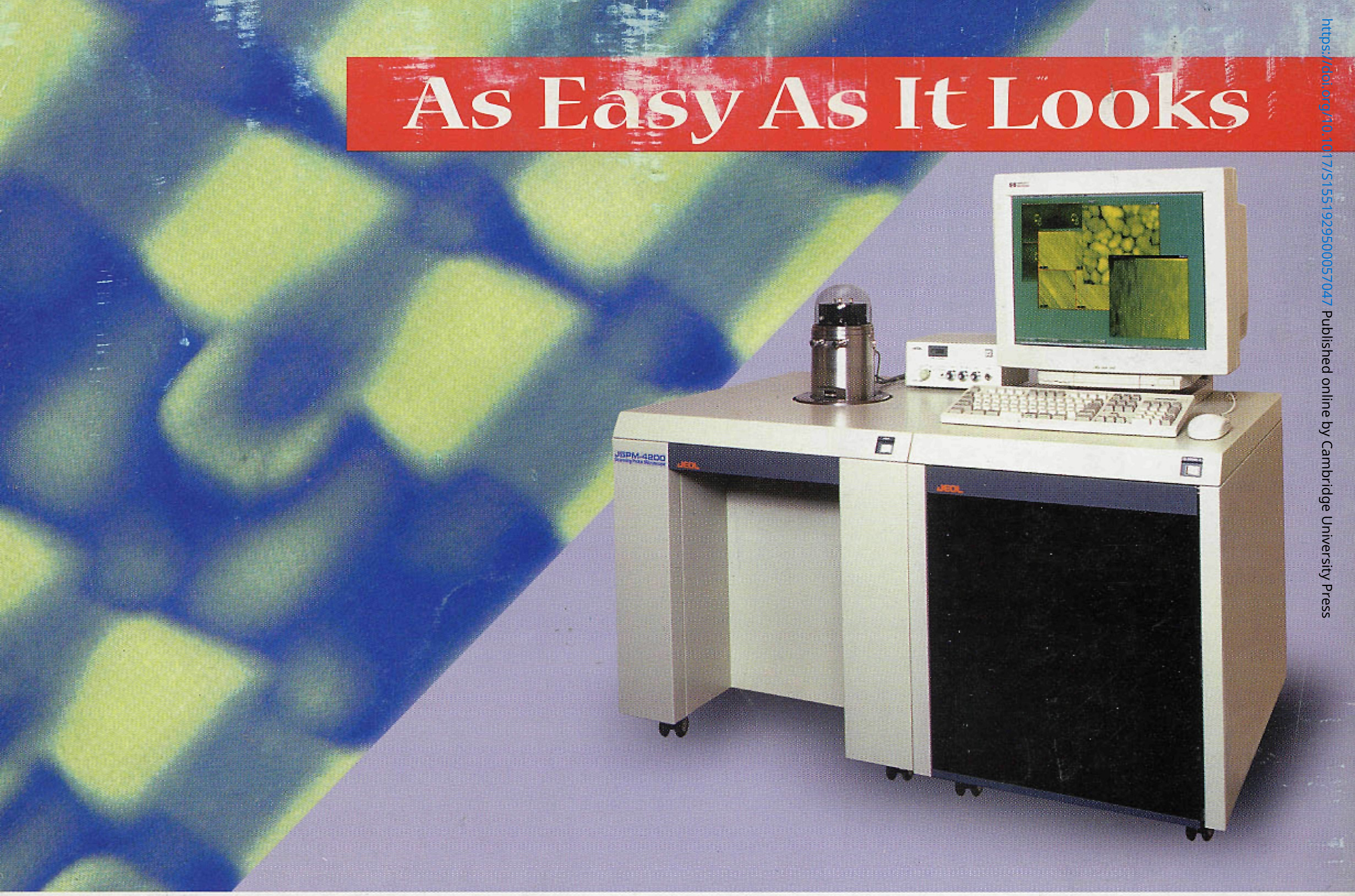
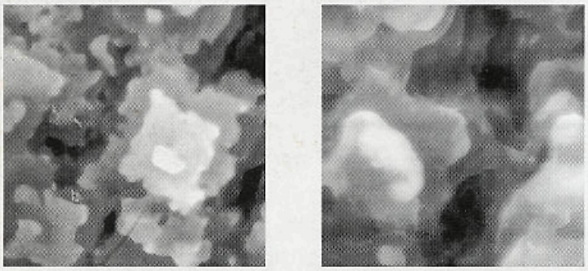
# As Easy As It Looks



## *NEW* – Multi-Environmental SPM Scanning Probe Microscope



*PEO at 60°C with evidence of melting clearly shown after 2 minutes.*

- ***Based on a Simple PC Interface.***
- ***Intuitive Operation with a Mouse Alone.***
- ***Capable of Imaging Under Either Ambient or High Vacuum and at Both High and Low Temperatures.***
- ***Fully Vibrationally Isolated.***
- ***Capable of Wet or Dry Imaging.***
- ***Variable Gas Pressure/Temperature.***

The new JSPM-4200 is a multipurpose turnkey Scanning Probe Microscope (SPM) capable of imaging using a myriad of different modes and accessories. Imaging modes include STM, STS (Scanning Tunneling Spectroscopy), CITS (Current Imaging Tunneling Microscopy), AFM, LFM (Lateral Force Microscopy), Non-contact Mode AFM, Discrete Contact Mode AFM, Lateral Modulation LFM, MFM (Magnetic Force Microscopy), and Force Modulation Microscopy.

If you would like to learn more about JEOL SPM's please give us a call and arrange for your own hands-on demonstration so that we can prove to you that it really is "As Easy As It looks".

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